



Michigan**Engineering**

Cyclic Vernier Time-to-Digital Converter Synthesized from a 65nm CMOS Standard Library

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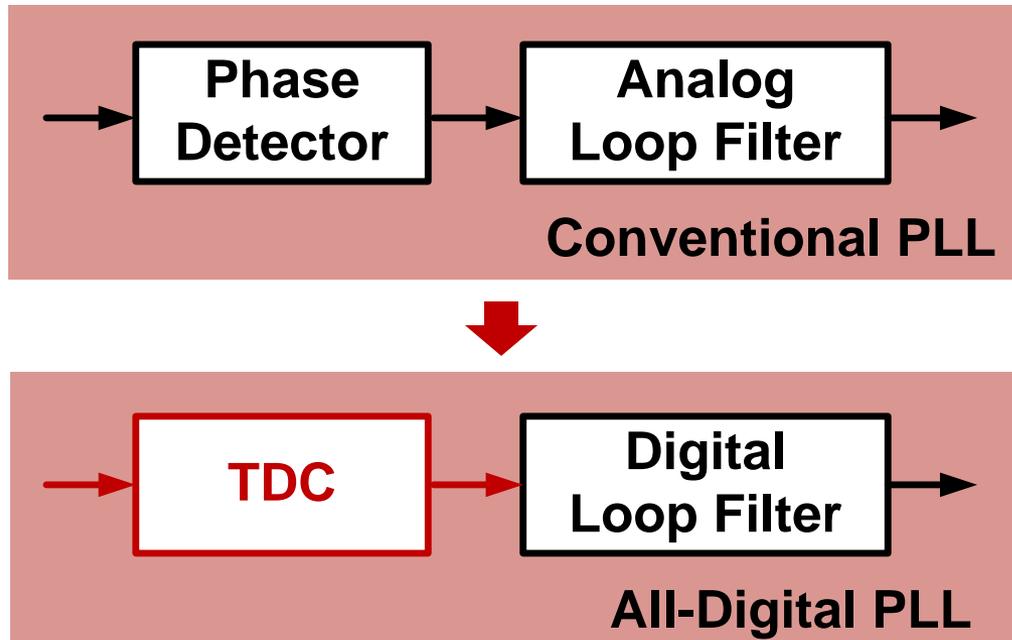
University of Michigan

Ann Arbor, MI, USA

ISCAS 2010

Time-to-Digital Converter

▶ Core building block in ADPLL



TDC + Digital LF



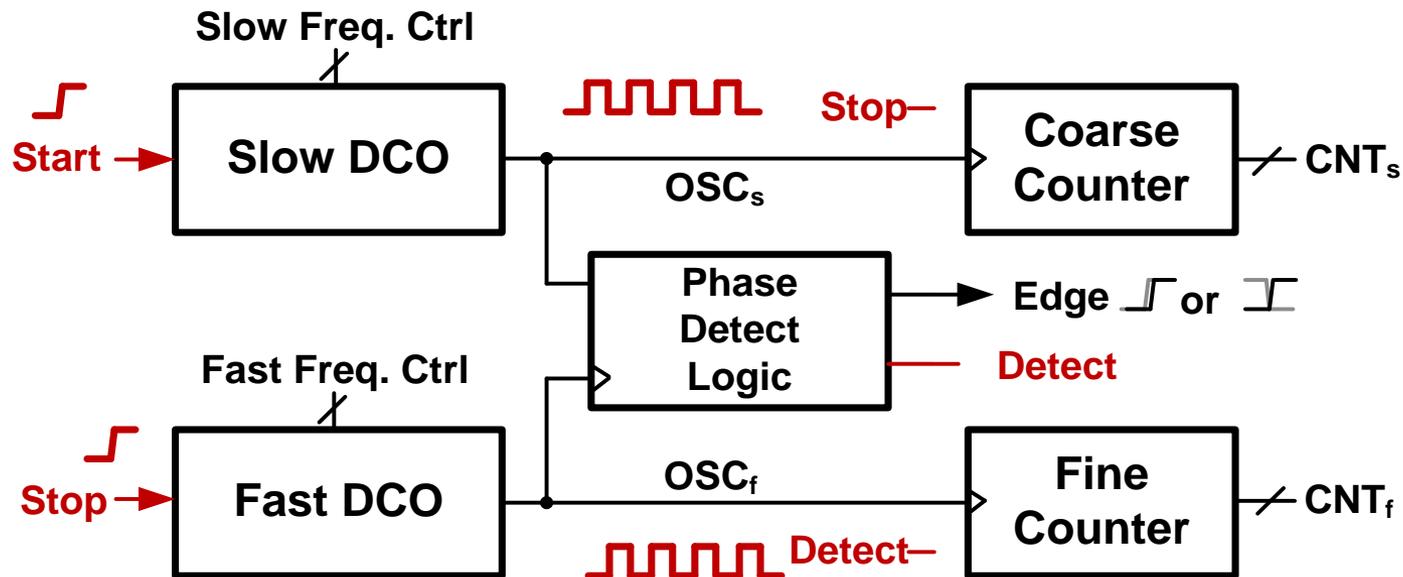
**Low power,
compact area
ADPLLs**

▶ Other applications

- ▶ Time-of-flight measurement, full speed testing, measurement instruments ...

TDC Block Diagram

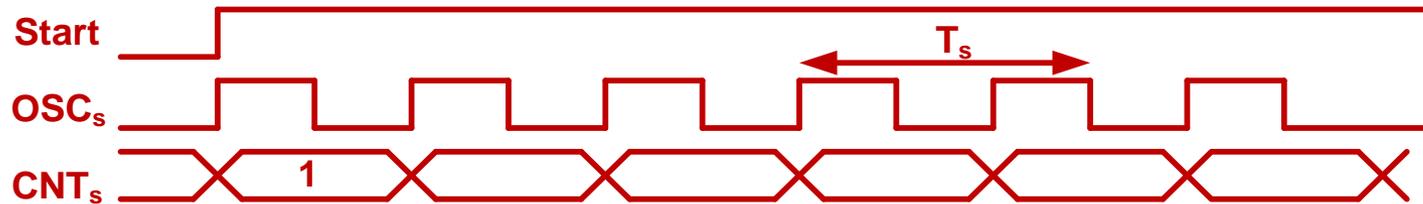
- ▶ Vernier ring time-to-digital converter
 - ▶ Resolution : difference between two oscillation periods



**Vernier Ring : high resolution,
large detectable range**

TDC Operation

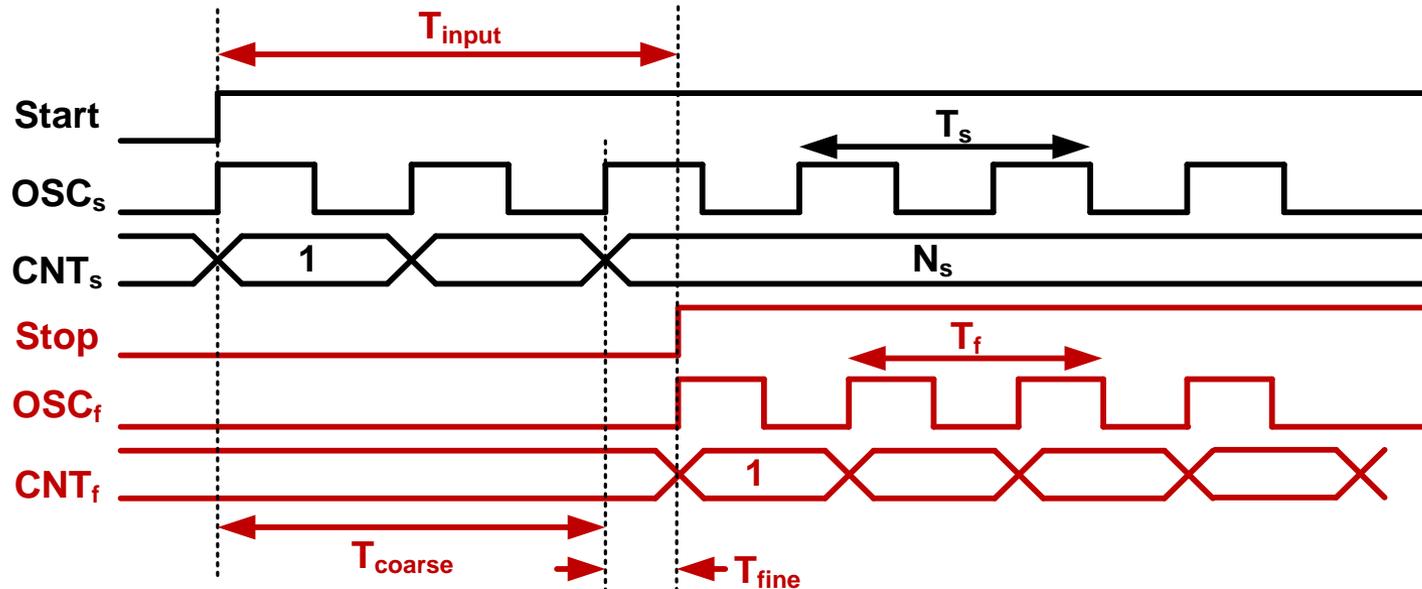
- ▶ Start arrives ...



Two step measurement
Coarse step : resolution of T_s

TDC Operation

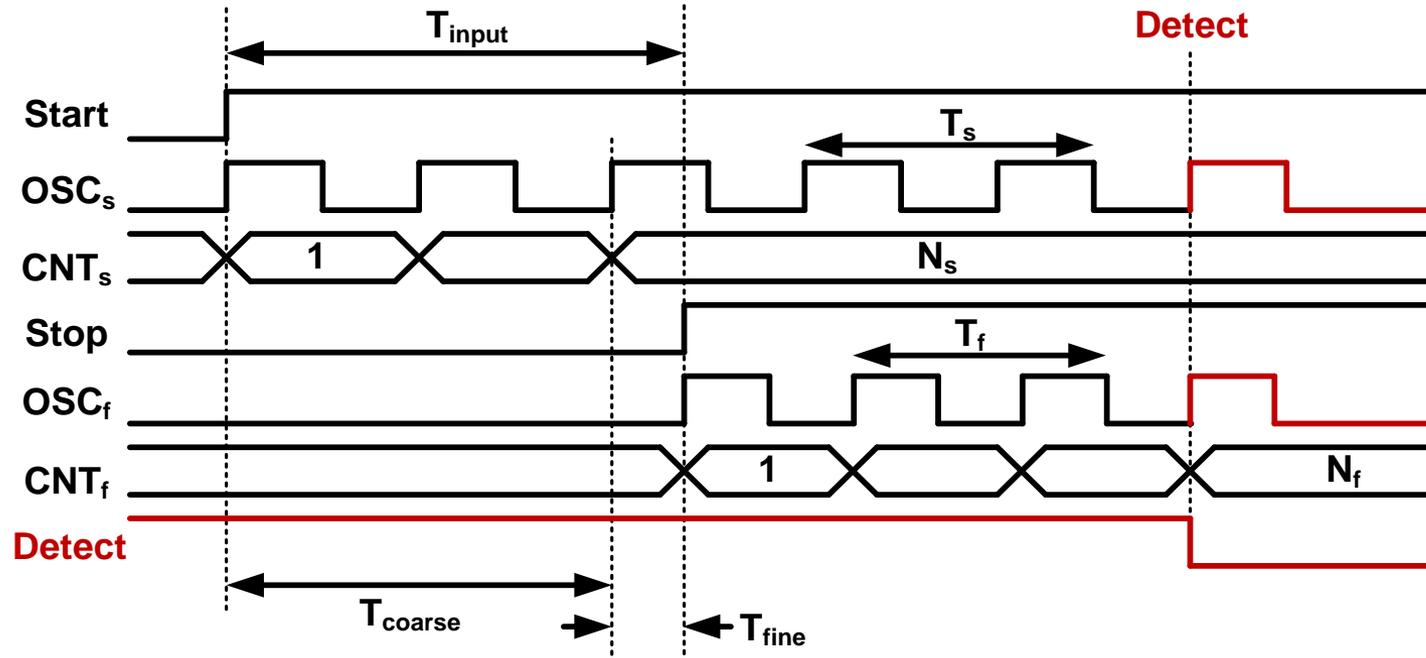
▶ Stop arrives ...



Two step measurement
Fine (Vernier) step : resolution of $T_s - T_f$

TDC Operation

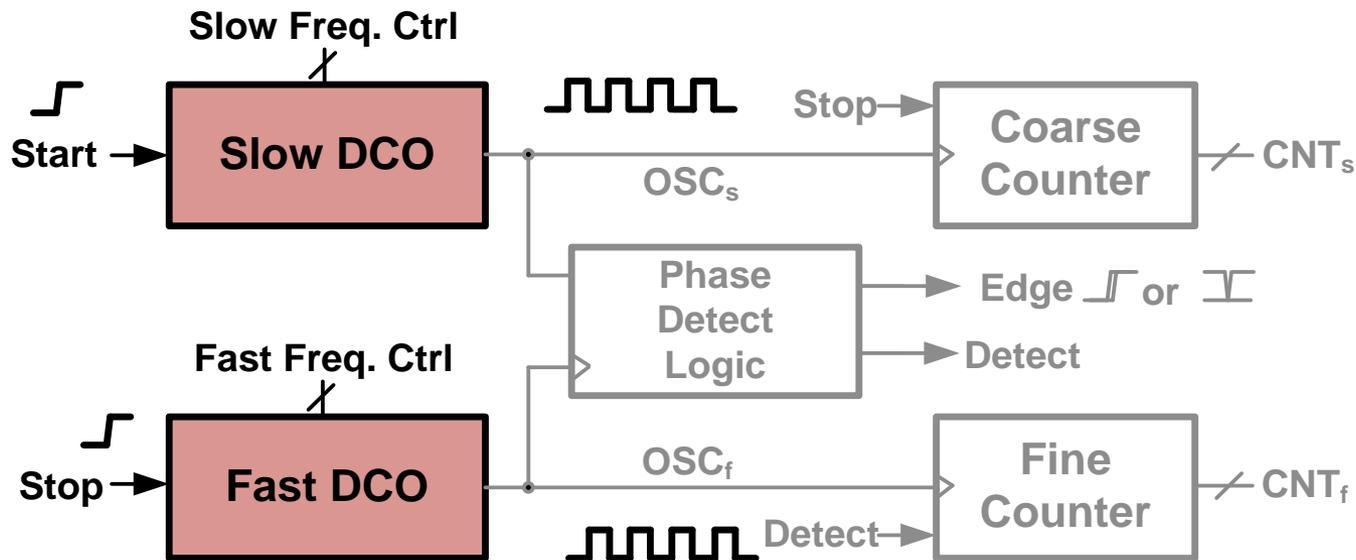
▶ Edge detected



$$T_{input} = N_s T_s + N_f (T_s - T_f)$$

Digitally Controlled Oscillator

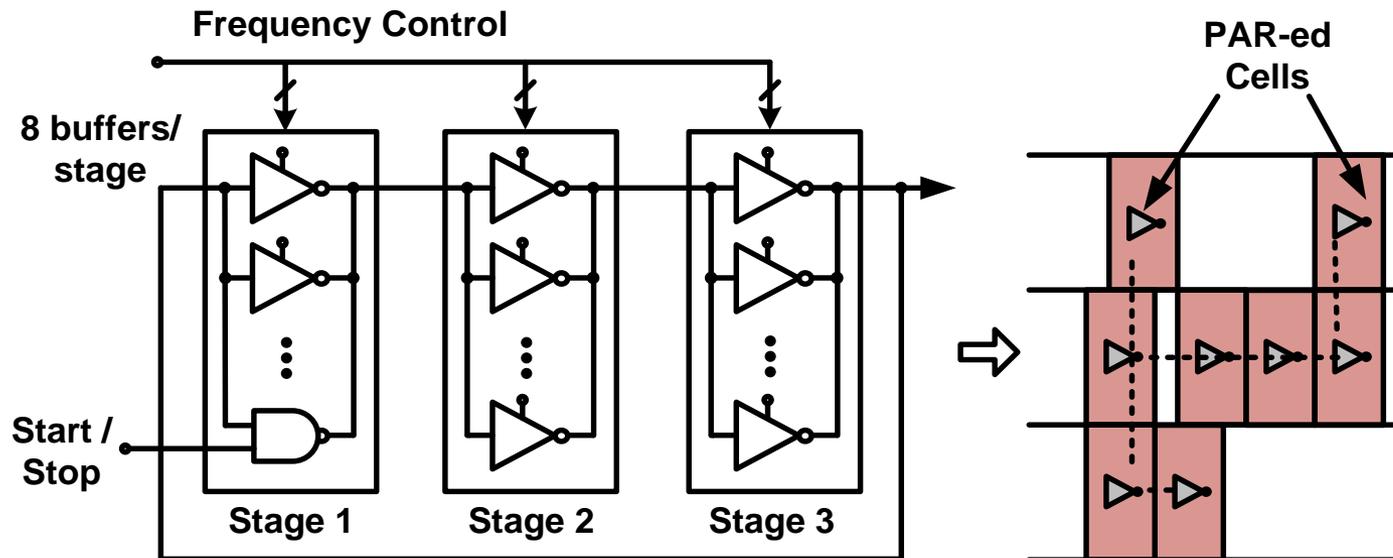
- ▶ Digitally controlled frequency
 - ▶ Reconfigurable coarse/fine resolution



**Reconfigurable
TDC performance**

Digitally Controlled Oscillator

- ▶ Implemented with **standard cells**
 - ▶ Parallel tri-state buffers



Cell-based DCO :
Automatic PAR, portable to other designs

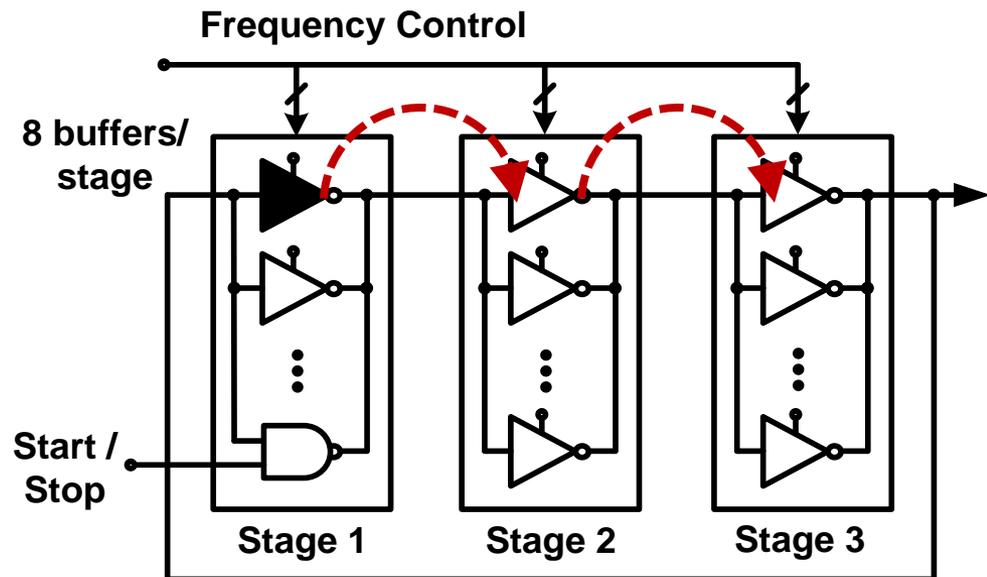
Effective Drive Strength

- ▶ Effective drive strength is measured by built-in counters

Turning off each buffer
increases period by
different amount



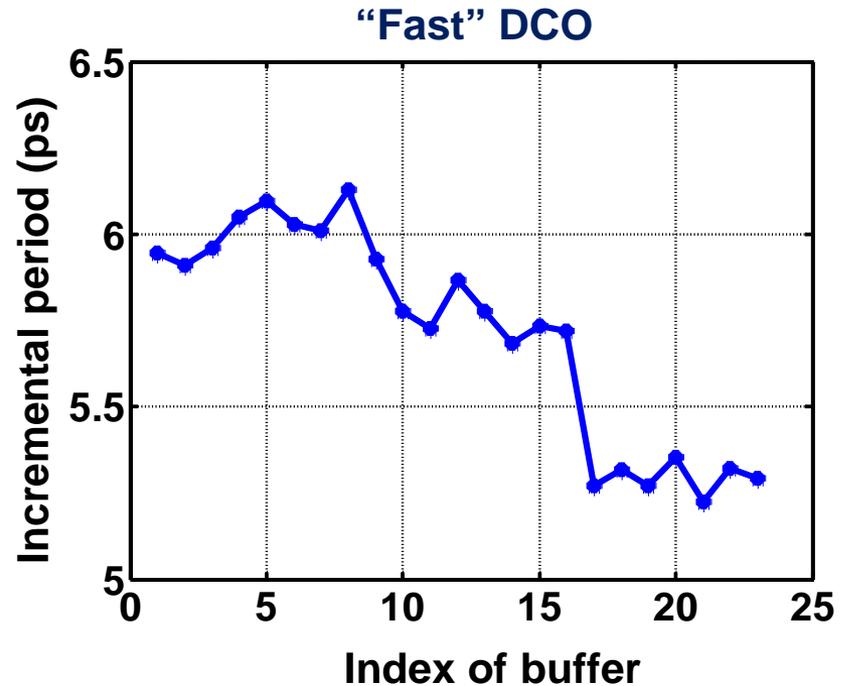
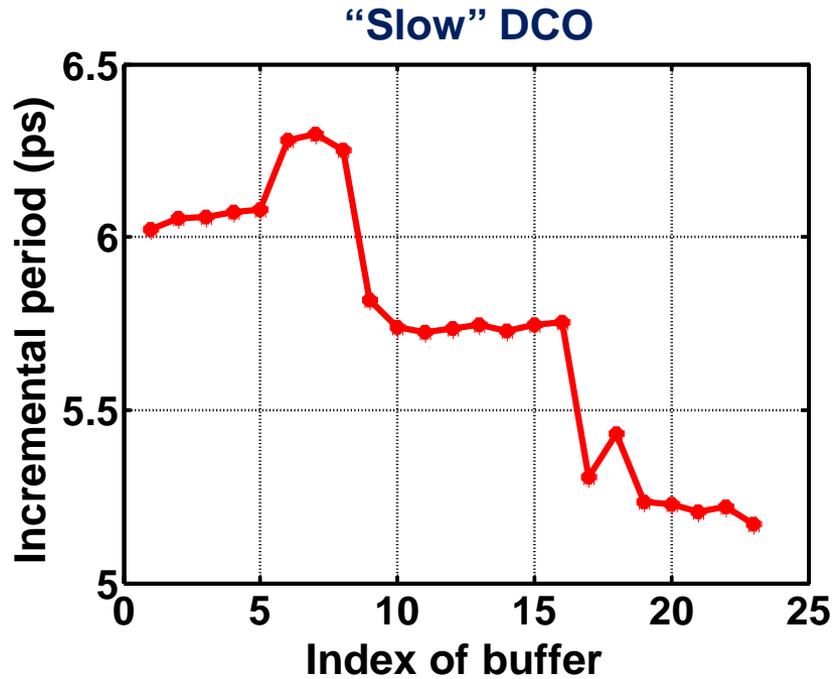
“Effective drive strength”



**Each buffer has different drive strength
due to automatic PAR**

Measured Incremental Period

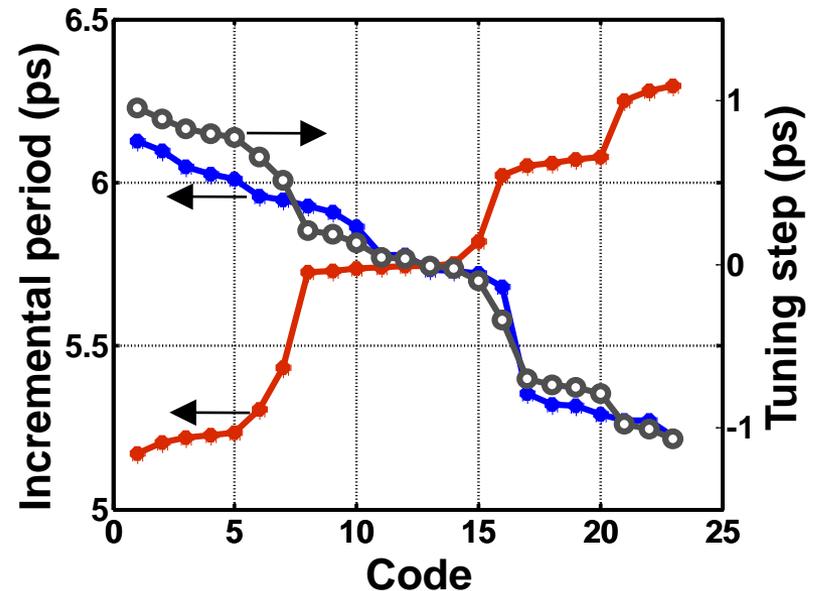
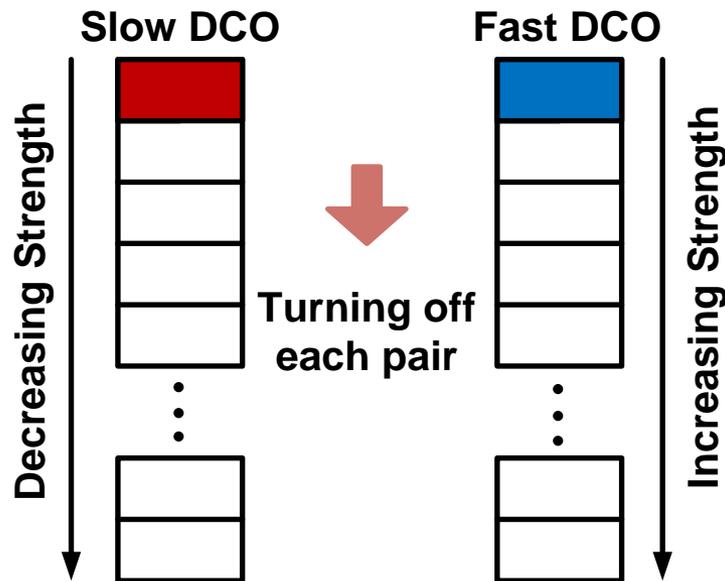
- ▶ Systematic mismatch observed



Utilized for calibration

Calibration of TDC Fine Step Resolution

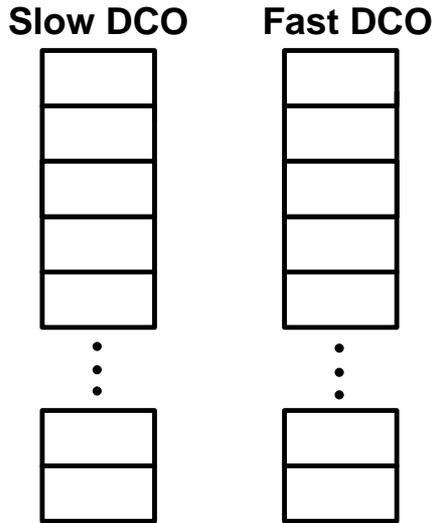
- ▶ Buffers are sorted based on measured drive strength
 - ▶ Provides a simplified calibration scheme



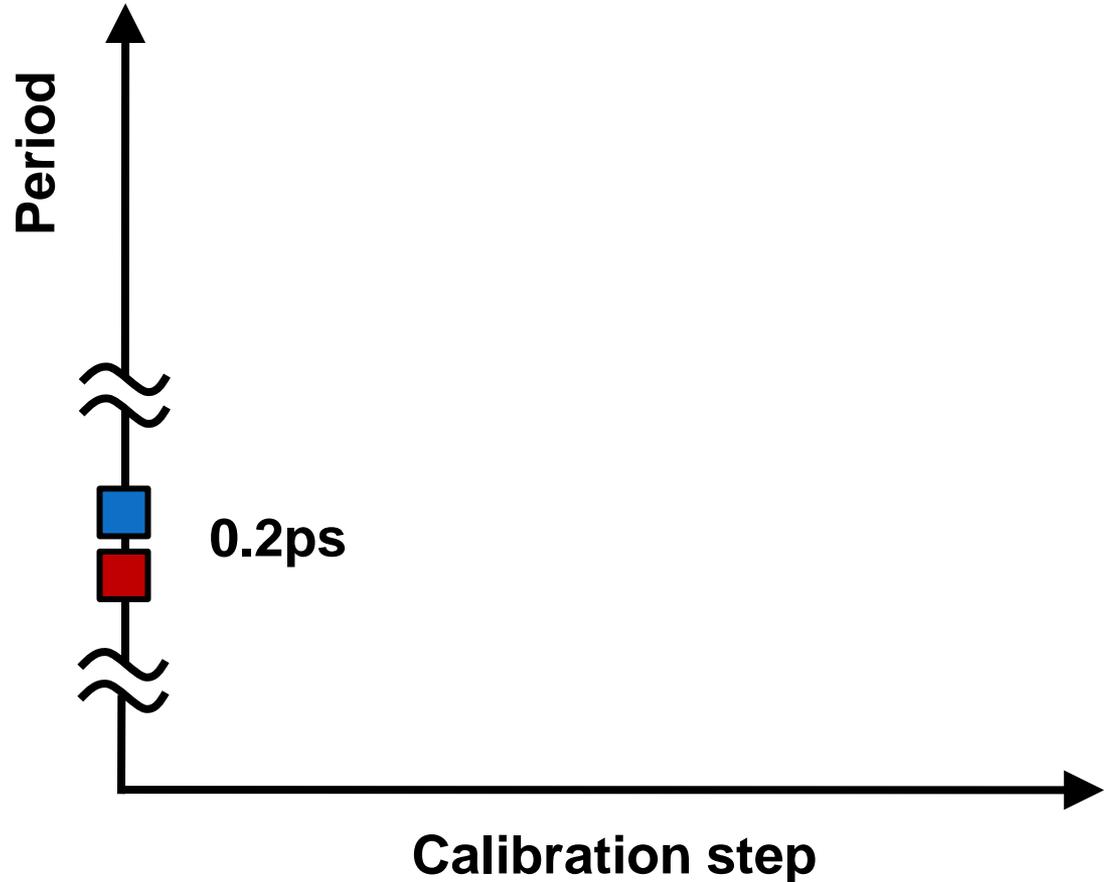
Calibrates $T_s - T_f$

Calibration Example

- ▶ Fine step resolution calibrated
 - ▶ Initial mismatch is observed



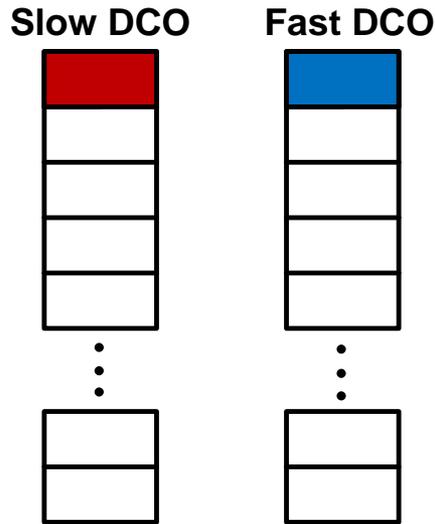
Target :
 $T_s - T_f = 1\text{ps}$



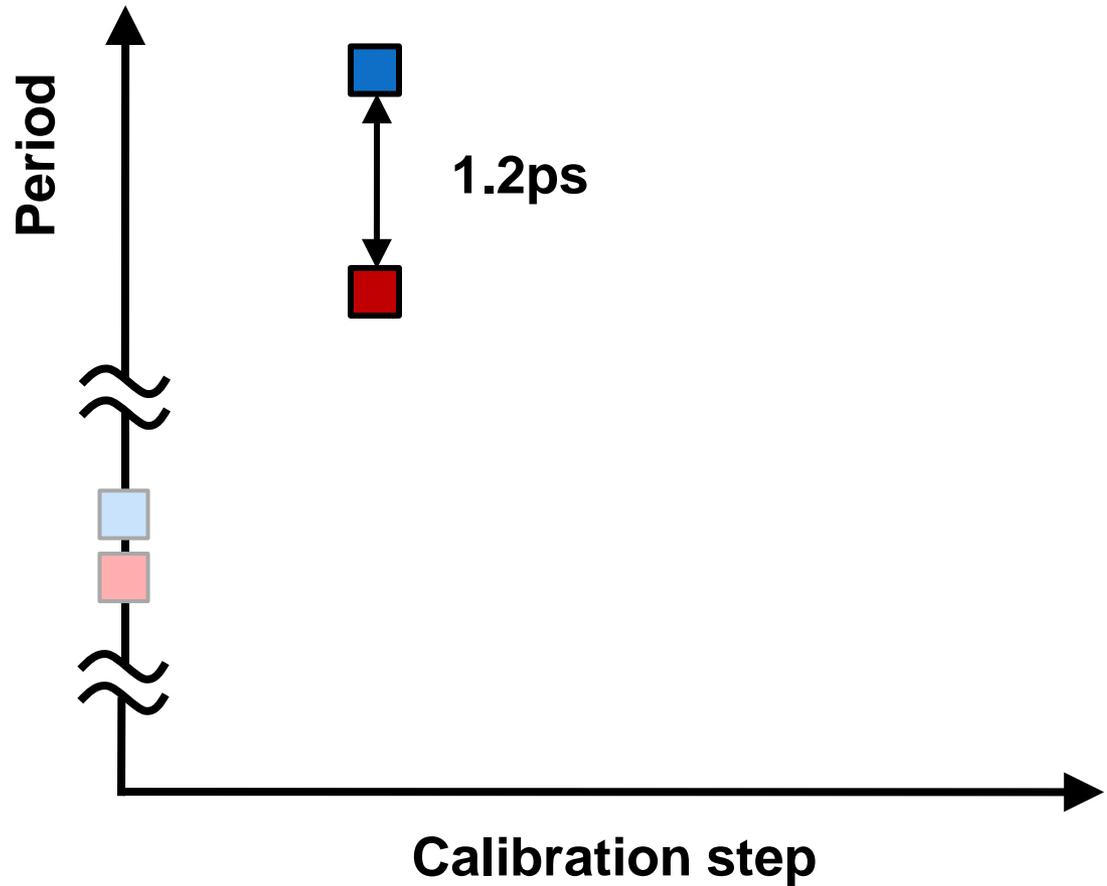
Calibration Example

- ▶ Fine step resolution calibrated

- ▶ 1st pair is turned off



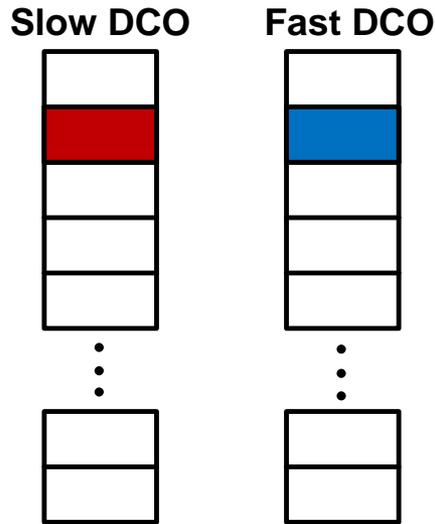
Target :
 $T_s - T_f = 1\text{ps}$



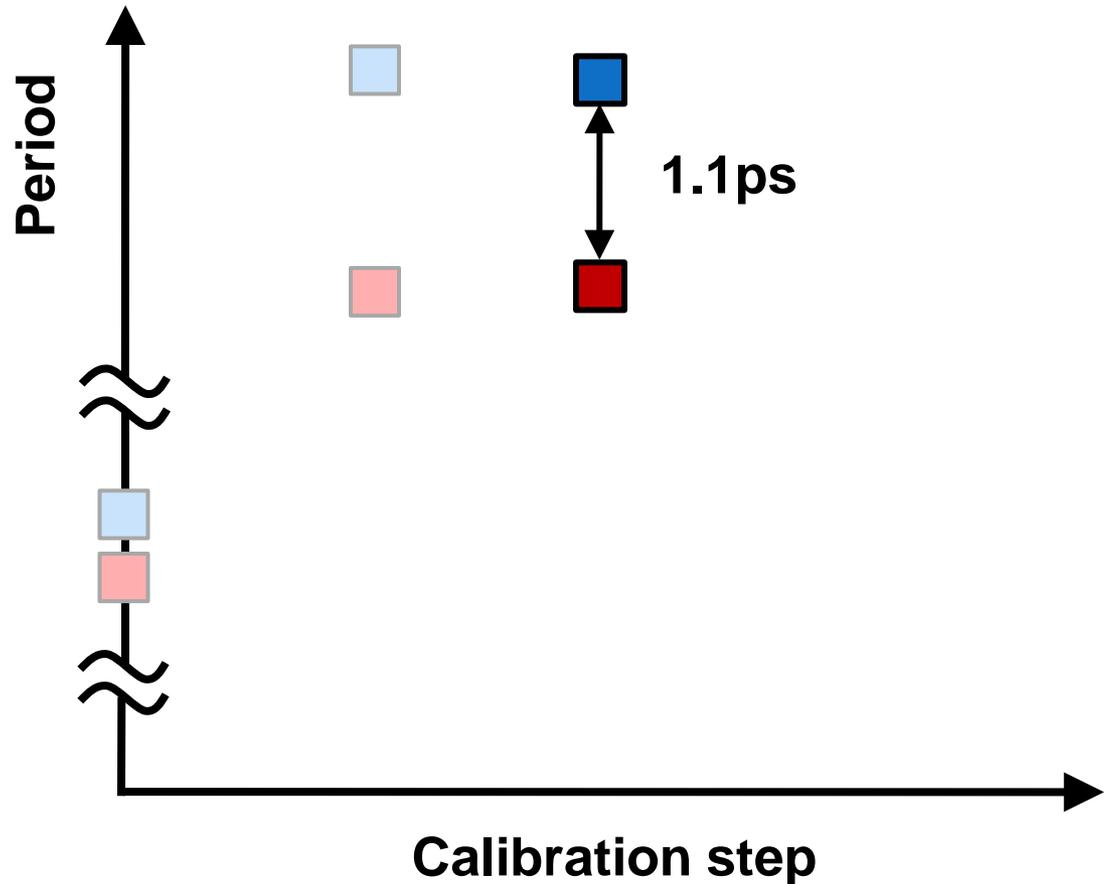
Calibration Example

- ▶ Fine step resolution calibrated

- ▶ 2nd pair is turned off



Target :
 $T_s - T_f = 1\text{ps}$

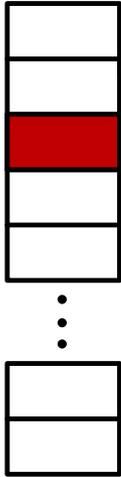


Calibration Example

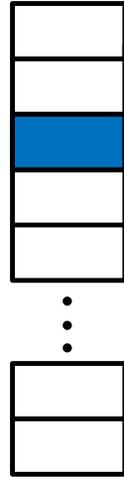
- ▶ Fine step resolution calibrated

- ▶ 3rd pair is turned off

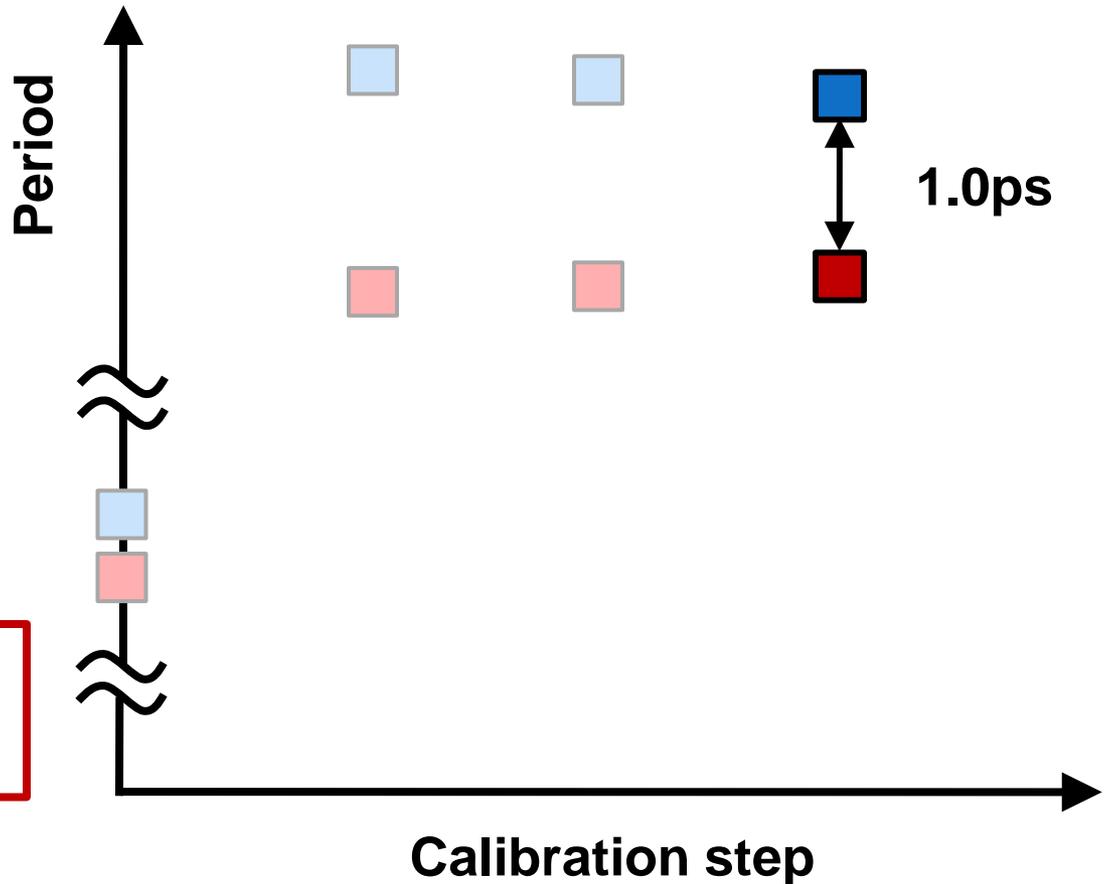
Slow DCO



Fast DCO

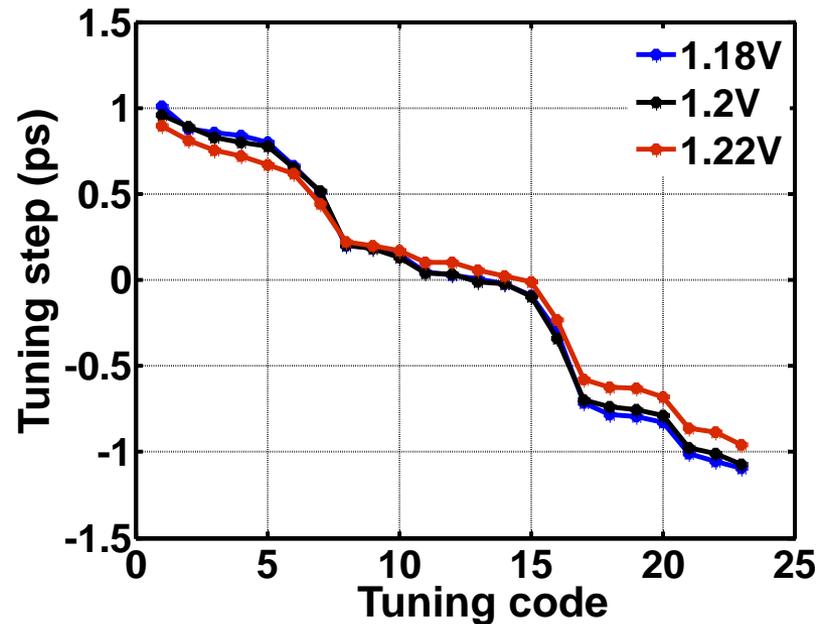
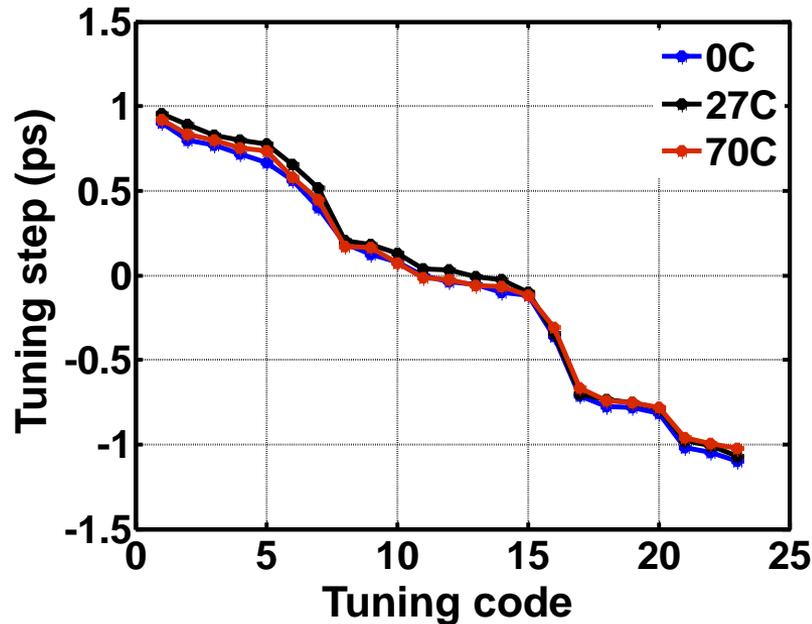


**Fine & monotonic
steps**



Temperature/Supply Variation

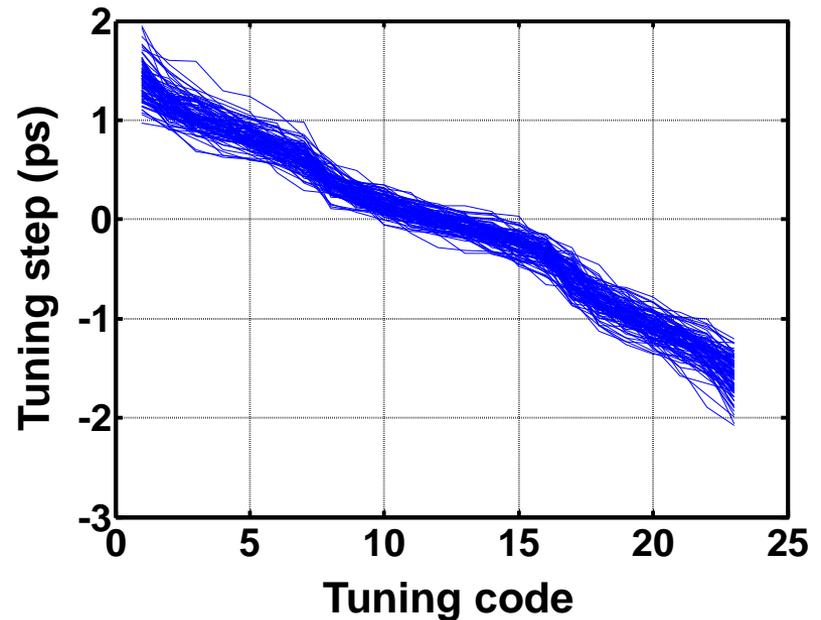
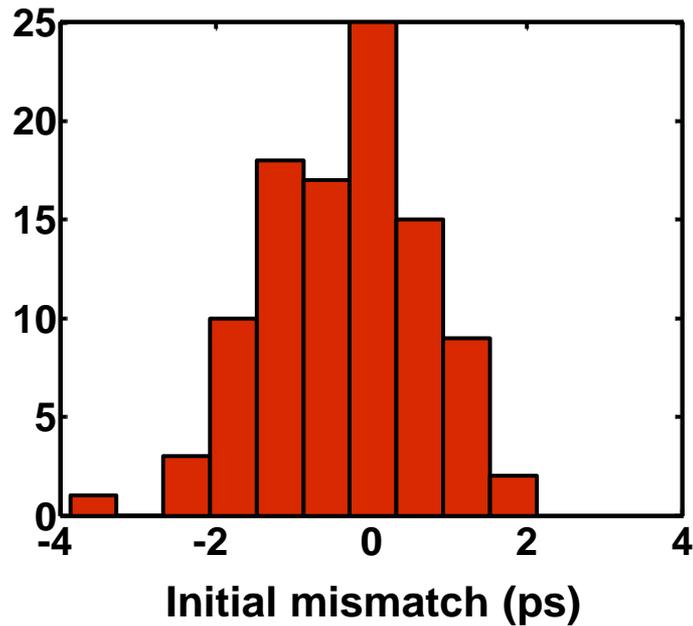
▶ Tuning steps over temperature/supply variation



**Tuning step is invariant
over temperature/supply variation**

Process variation

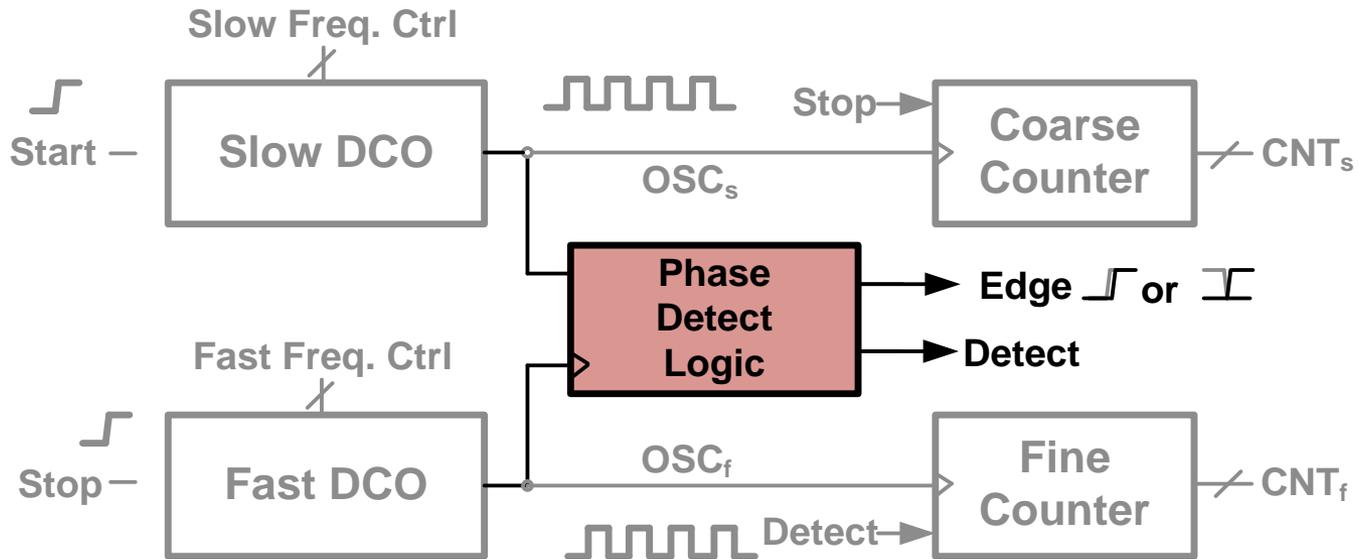
- ▶ Monte Carlo simulation over process variation



**TDC resolution can be tuned
over process variation**

Phase Detect Logic

- ▶ Both rising/falling edges detected
 - ▶ Flip-flop and logic circuit

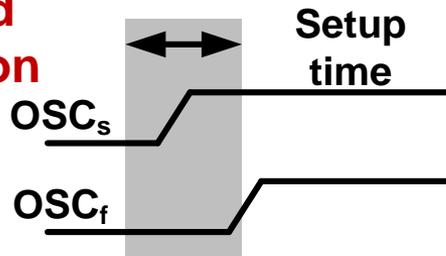


**Reduces required fine step range,
thus power consumption**

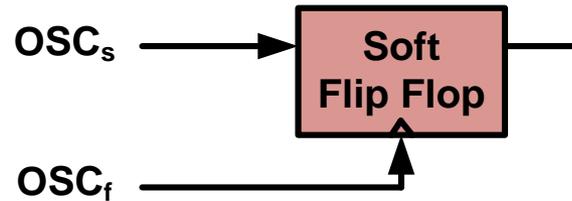
Soft Flip-Flop

- ▶ Cannot detect edge within setup time of standard FF

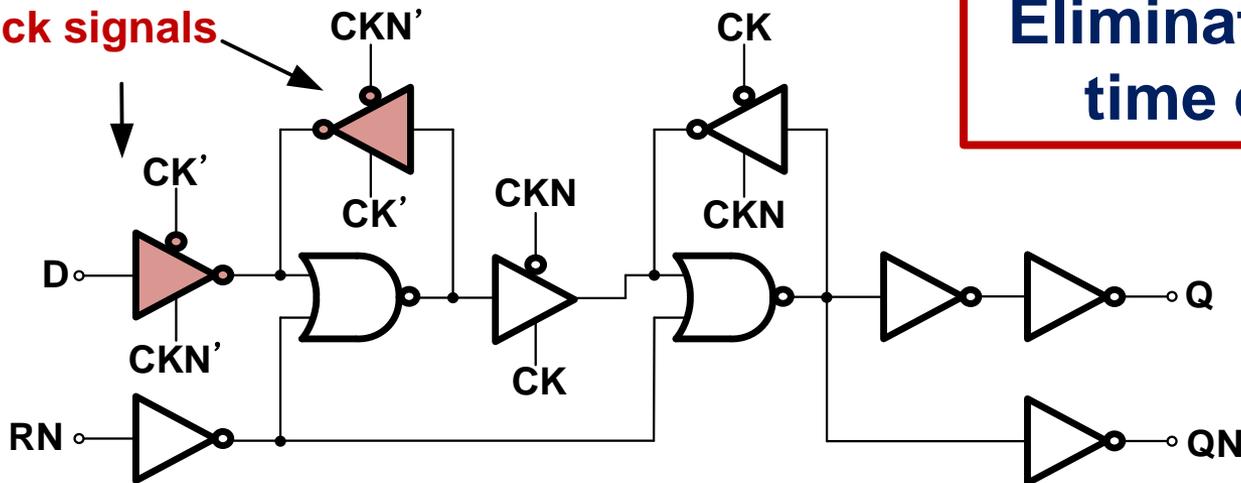
Missed detection



Setup time ~ 0



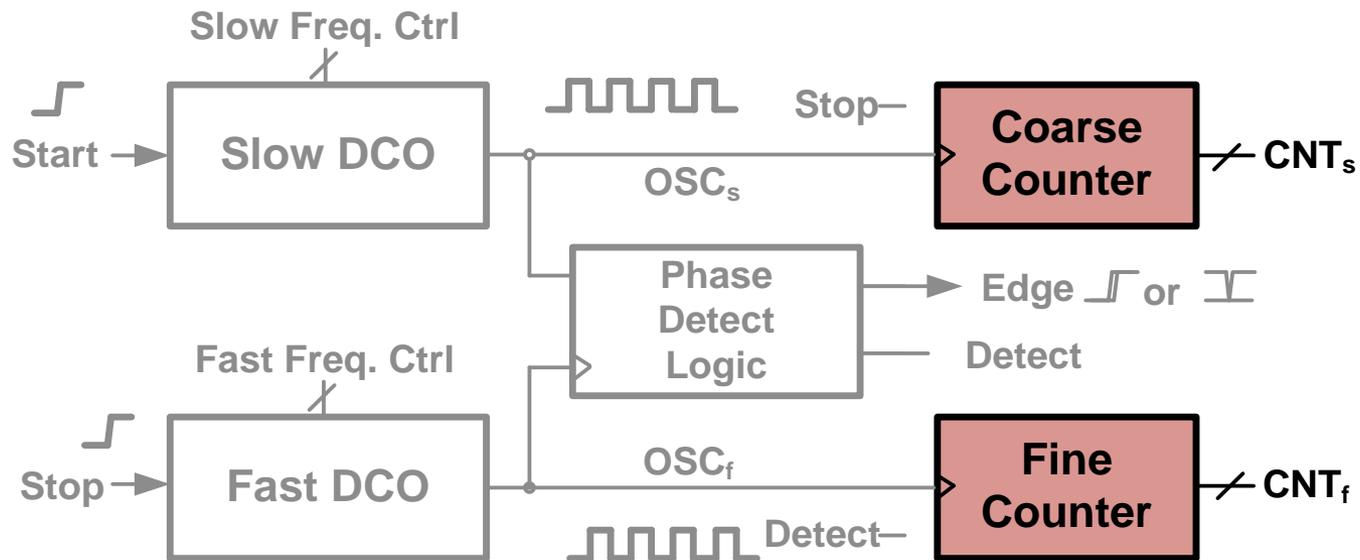
Delayed clock signals



Eliminate setup time effect

Counters

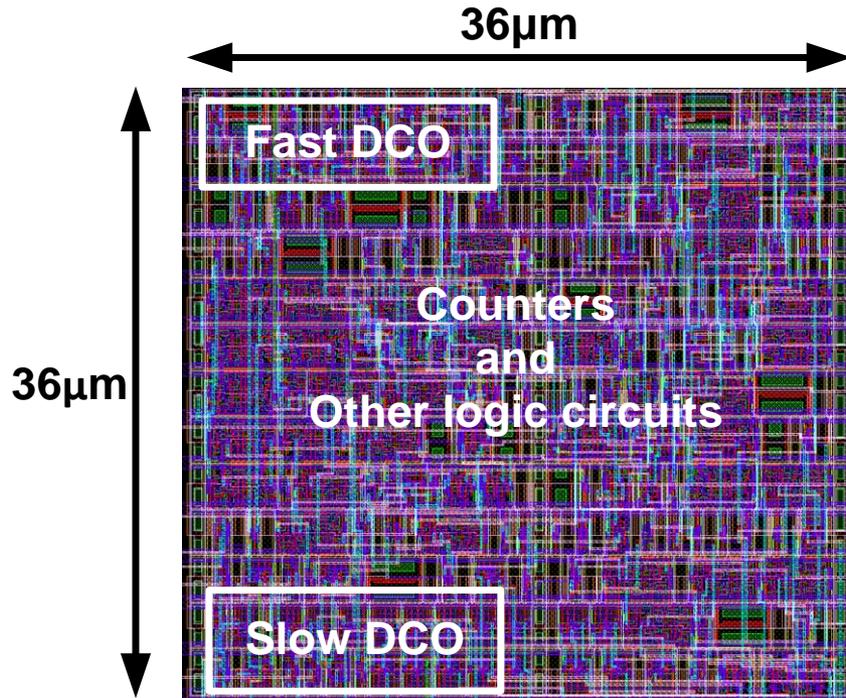
- ▶ Counts coarse/fine oscillations
 - ▶ In calibration mode, measure frequency, drive strength



Typical digital block

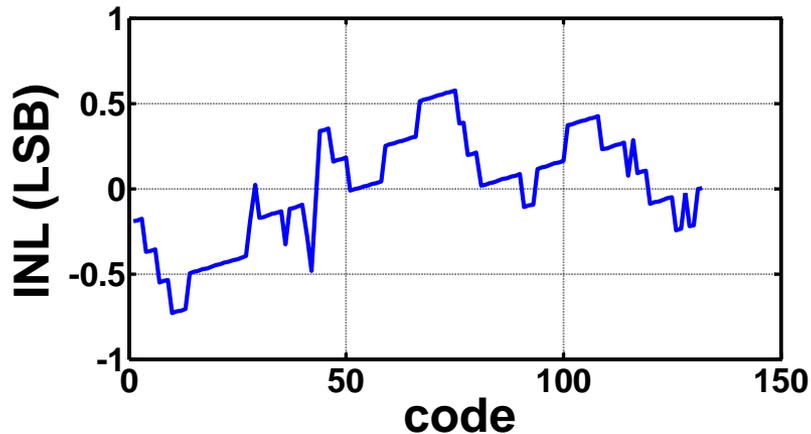
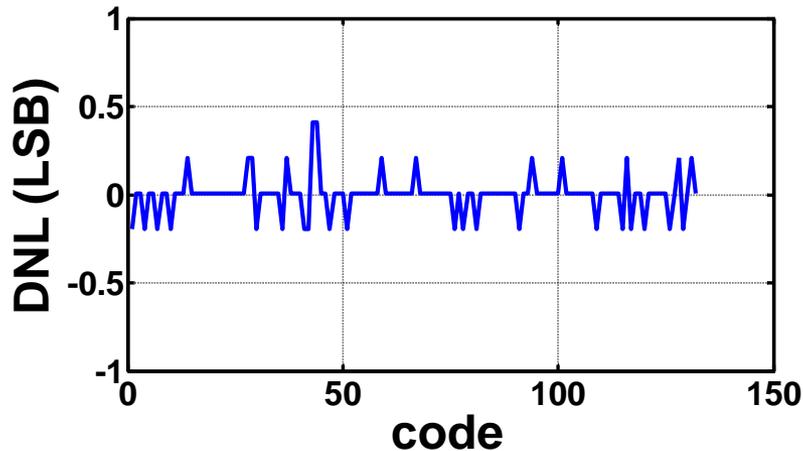
Automatic Place & Route

- ▶ All functional blocks are implemented with standard cells and automatically laid out
 - ▶ Can follow digital circuit design flow



Automatic PAR :
Simplified design,
higher integration

TDC Performance



| | |
|-------------------------|----------------|
| Process | 65nm CMOS |
| Technique | Cyclic Vernier |
| Resolution* | 1ps |
| DNL/INL (LSB) | 0.5 / 0.8 |
| Power (mW)** | 0.01 – 0.15 |
| Area (mm ²) | 0.001 |

* Calibrated at 1ps

** Power @ 1MHz sampling freq.
Both are reconfigurable

Conclusions

- ▶ High resolution, small area TDC
 - ▶ Cell-based design flow
 - ▶ Calibrated based on effective drive strength

| | This work | Lee JSSC 08 | Straayer JSSC 09 | Henzler ISSCC 08 |
|-------------------------|---------------------------|----------------|---------------------|----------------------|
| Process | 65nm CMOS | 90nm CMOS | 130nm CMOS | 90nm CMOS |
| Technique | Cyclic Vernier | Time Amp. | Gated RO | Passive Interpol. |
| Resolution | 1ps | 1.25ps | 6ps | 4.7ps |
| Power*(mW) | 0.01- 0.15 | 0.3 | 0.06-0.6 | 20 |
| Area (mm ²) | 0.001 | 0.6 | 0.04 | 0.02 |

*Normalized at 1MHz